Power MOSFET

40 V, Dual N-Channel, SOIC-8

Features

- Asymmetrical N Channels
- Low R_{DS(on)}
- Low Capacitance
- Optimized Gate Charge
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

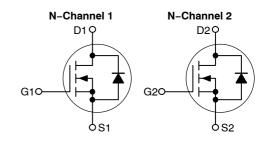
	V _{(BR)DSS}	R _{DS(on)} Max	I _D Max (Notes 1 and 2)
Channel 1	40 V	12 mΩ @ 10 V	11 A
		16 mΩ @ 4.5 V	
Channel 2	40 V	20 mΩ @ 10 V	6.5 A
		36.5 mΩ @ 4.5 V	

- Surface-mounted on FR4 board using 1 in sq pad size (Cu area = 1.127 in sq [2 oz] including traces)
- Only selected channel is been powered
 1W applied on channel 1: T_J = 1 W * 85°C/W + 25°C = 110°C



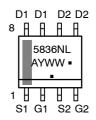
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MARKING DIAGRAM* AND PIN ASSIGNMENT





A = Assembly Location

Y = Year WW = Work Week • = Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMD5836NLR2G	SOIC-8 (Pb-Free)	2500 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Parameter	Symbol	Ch 1	Ch 2	Unit		
Drain-to-Source Voltage	V_{DSS}	40	40	V		
Gate-to-Source Voltage	V_{GS}	±20	±20	V		
Continuous Drain Current R _{0JA} (Notes 3 and 4)	Steady	T _A = 25°C	I _D	9.0	5.7	Α
	State	T _A = 70°C		7.2	4.6	1
Power Dissipation R _{0JA} (Notes 3 and 4)	wer Dissipation $R_{\theta JA}$ (Notes 3 and 4) $T_A = 25^{\circ}C$		P_{D}	1.5	1.5	W
		T _A = 70°C		0.9	0.9	
Continuous Drain Current R _{0JA} (Notes 3 and 4)	ous Drain Current $R_{\theta JA}$ (Notes 3 and 4) $t \le 10s$ $T_A = 25^{\circ}$		I _D	11	6.5	Α
		T _A = 70°C	1	8.6	4.6	1
Power Dissipation R _{0JA} (Notes 3 and 4)		T _A = 25°C	P_{D}	2.1	1.9	W
		T _A = 70°C	1	1.3	1.2	1
Pulsed Drain Current	t _p = 10 μs		I _{DM}	43	26	Α
Operating Junction and Storage Temperature	T _J , T _{STG}	-55 to	+150	°C		
Source Current (Body Diode)	IS	10	7.0	Α		
Single Pulse Drain-to-Source Avalanche Energy (V_{DD} = 40 V, V_{GS} = 10 V, L = 0.1 mH)				76	22	mJ
			I _{AS}	39	21	Α
Lead Temperature for Soldering Purposes (1/8" from cas	se for 10s)		TL	20	60	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

- 3. Surface-mounted on FR4 board using 1 in sq pad size (Cu area = 1.127 in sq [2 oz] including traces)

Only selected channel is been powered
 1W applied on channel 1: T_J = 1 W * 85°C/W + 25°C = 110°C

THERMAL RESISTANCE RATINGS

Parameter	Symbol	Ch 1	Ch 2	Unit
Junction-to-Ambient Steady State (Notes 5 and 7)	$R_{ heta JA}$	85	86	°C/W
$Junction-to-Ambient-t \leq 10 s \text{ (Notes 5 and 7)}$	$R_{ heta JA}$	60	65	
Junction-to-Ambient Steady State (Notes 5 and 8)	$R_{ heta JA}$	59		
Junction-to-Ambient Steady State (Notes 6 and 7)	$R_{ heta JA}$	136	136	1

- 5. Surface-mounted on FR4 board using 1 in sq pad size (Cu area = 1.127 in sq [2 oz] including traces)
- 6. Surface-mounted on FR4 board using 0.155 in sq (100 mm²) pad size
- 7. Only selected channel is been powered
- 1W applied on channel 1: $T_J = 1 \text{ W} * 85^{\circ}\text{C/W} + 25^{\circ}\text{C} = 110^{\circ}\text{C}$ 8. Both channels receive equivalent power dissipation
- - 1 W applied on each channel: T_{.1} = 2 W * 59°C/W + 25°C = 143°C

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Co	ndition	Ch	Min	Тур	Max	Unit
OFF CHARACTERISTICS							•	•
Drain-to-Source Breakdown	V _{(BR)DSS}	V _{GS} = 0 V, I _D = 250 μA		Ch 1	40			V
Voltage		VGS = 0 V, I	D = 250 μA	Ch 2				
Drain-to-Source Breakdown	V _{(BR)DSS}			Ch 1		146		mV/
Voltage Temperature Coefficient	T _J			Ch 2		25		°C
Zero Gate Voltage Drain Current	I _{DSS}		T _J = 25°C	Ch 1			1.0	μΑ
		$V_{GS} = 0 V$, $V_{DS} = 40 V$	1) = 25 0	Ch 2				
		$V_{DS} = 40 \text{ V}$	T _J = 125°C	Ch 1			100	
			1) = 125 0	Ch 2				
Gate-to-Source Leakage Current	I _{GSS}	V 0VV	+ 20 M	Ch 1			±100	nA
		$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$		Ch 2				
ON CHARACTERISTICS (Note 9)	<u>-</u>					-	-	
Gate Threshold Voltage	V _{GS(TH)}	VGS = VDS, I _D = 250 μA		Ch 1	1.0	1.8	3.0	V
		VGS = VDS,	s, I _D = 250 μA	Ch 2	1.0	1.8	3.0	
Negative Threshold Temperature	V _{GS(TH)} / T _J			Ch 1		6.0		mV/°C
Coefficient	IJ			Ch 2		6.0		
Drain-to-Source On Resistance	R _{DS(on)}	$V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$		Ch 1		9.5	12	mΩ
		V _{GS} = 10 \	/, I _D = 7 A	Ch 2		16.2	20	
		V _{GS} = 4.5 \	/, I _D = 10 A	Ch 1		13	16	mΩ
		V _{GS} = 4.5	V, I _D = 7 A	Ch 2		25.0	36.5	
Forward Transconductance	9 _{FS}	V _{DS} = 15 V	', I _D = 10 A	Ch 1		10.5		S
		V _{DS} = 15 V, I _D = 7 A		Ch 2		6.0		
CHARGES, CAPACITANCES & GAT	TE RESISTANC	E				-		
Input Capacitance	C _{ISS}			Ch 1		2120		pF
				Ch 2		730		
Output Capacitance	C _{OSS}	V _{GS} = 0 V, f = 20	1 MHz, V _{DS} =	Ch 1		315		
		20	V	Ch 2		123		
Reverse Transfer Capacitance	C _{RSS}			Ch 1		225		
				Ch 2		84		

^{9.} Pulse Test: pulse width $\leq 300~\mu s,$ duty cycle $\leq 2\%$ 10. Switching characteristics are independent of operating junction temperatures

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition	Ch	Min	Тур	Max	Unit
CHARGES, CAPACITANCES & C	GATE RESISTANC	E					
Total Gate Charge	Q _{G(TOT)}	$V_{GS} = 10V, V_{DS} = 20V, I_{D}$	= 10A Ch 1		36	50	nC
		V _{GS} = 10 V, V _{DS} = 20 V, I _E	o = 7 A Ch 2		16		1
			Ch 1		15	23	1
			Ch 2		8.5	11	1
Threshold Gate Charge	Q _{G(TH)}		Ch 1		2.4		1
			Ch 2		1.0		
Gate-to-Source Charge	Q _{GS}	V _{GS} = 4.5 V, V _{DS} = 20 V,	CH1: Ch 1		6.9		
		I _D = 10 A, CH2: I _D = 7	A Ch 2		2.8		
Gate-to-Drain Charge	Q_{GD}		Ch 1		7.2		
			Ch 2		4.0		1
Plateau Voltage	V_{GP}		Ch 1		3.2		V
					3.3		
Gate Resistance	R _G		Ch 1		1.2		Ω
			Ch 2		2.1		1
SWITCHING CHARACTERISTIC	S (Note 10)						
Turn-On Delay Time	t _{d(ON)}		Ch 1		16		ns
			Ch 2		11.5		
Rise Time	t _r		Ch 1		22		
		$V_{GS} = 4.5 \text{ V}, V_{DD} = 20 \text{ V},$ $I_D = 10 \text{ A}, \text{ CH2: } I_D = 7 \text{ A},$	CH1: Ch 2		14		
Turn-Off Delay Time	t _{d(OFF)}	$10 = 10 \text{ A}, \text{ OHZ. 10} = 7 \text{ A},$ 2.5Ω	Ch 1		26		
			Ch 2		15.5		
Fall Time	t _f		Ch 1		8.5		
			Ch 2		3.5		
DRAIN-SOURCE DIODE CHARA	ACTERISTICS						
Forward Diode Voltage	V _{SD}	Vcs = 0 V. T _J = 2	Ch 1		0.9	1.2	V
		CH1: I _D =	Ch 2		0.85	1.2	
		10 A, CH2: I _D = 7 A T ₁ = 1	Ch 1		0.65		
		$= 7 \text{ A}$ $T_{\text{J}} = 1$	Ch 2		0.73		
Reverse Recovery Time	t _{RR}		Ch 1		27		ns
			Ch 2		17		
Charge Time	Ta		Ch 1		14		
		V _{GS} = 0 V, dISD/dt = 100	A/μs, Ch 2		11		
Discharge Time	T _b	CH1: I _D = 10 A, CH2: I _D :	= 7 A Ch 1		13		
			Ch 2		6.0		<u> </u>
Reverse Recovery Charge	Q _{RR}		Ch 1		19		nC
			Ch 2		9.0]

^{9.} Pulse Test: pulse width $\leq 300~\mu s,$ duty cycle $\leq 2\%$ 10. Switching characteristics are independent of operating junction temperatures

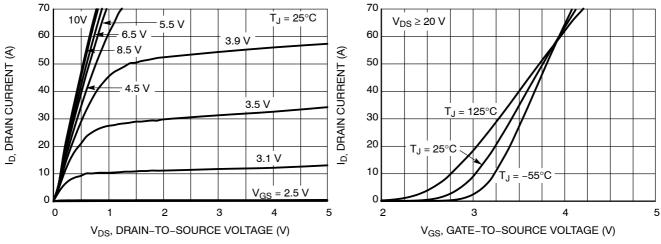


Figure 1. On–Region Characteristics – Channel 1

Figure 2. Transfer Characteristics - Channel 1

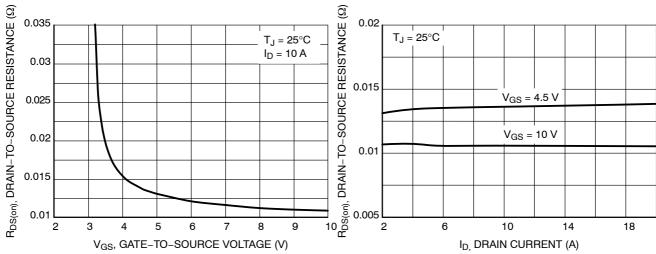


Figure 3. On-Resistance vs. Gate-to-Source Voltage - Channel 1

Figure 4. On-Resistance vs. Drain Current and Gate Voltage – Channel 1

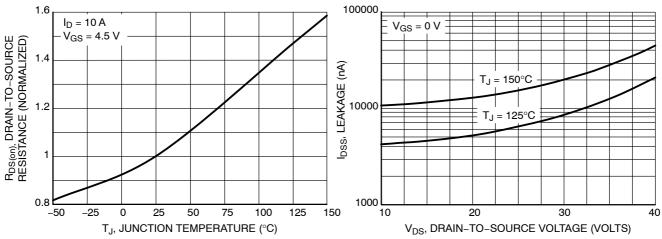


Figure 5. On–Resistance Variation with Temperature – Channel 1

Figure 6. Drain-to-Source Leakage Current vs. Voltage - Channel 1

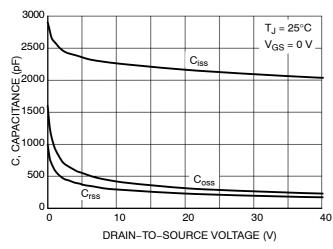


Figure 7. Capacitance Variation - Channel 1

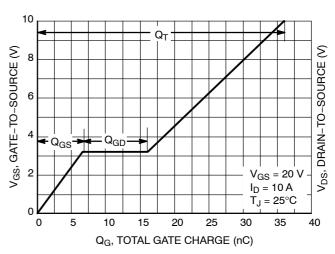


Figure 8. Gate-To-Source and
Drain-To-Source Voltage vs. Total Charge Channel 1

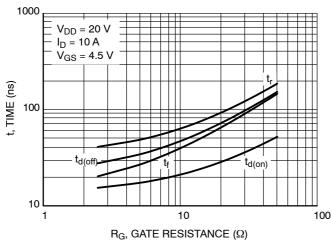


Figure 9. Resistive Switching Time Variation vs. Gate Resistance – Channel 1

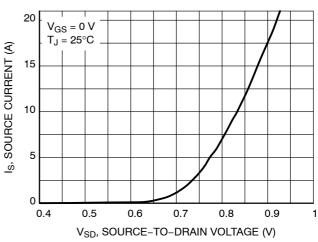


Figure 10. Diode Forward Voltage vs. Current
- Channel 1

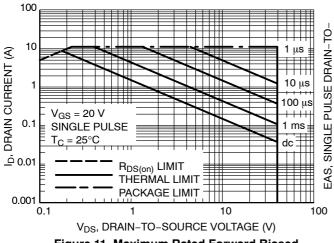


Figure 11. Maximum Rated Forward Biased Safe Operating Area – Channel 1

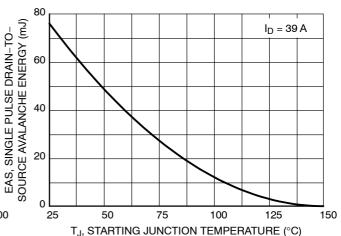


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature – Channel 1

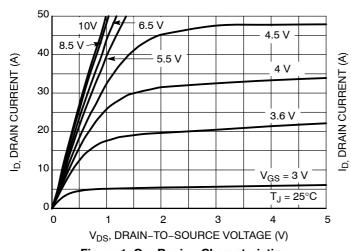


Figure 1. On–Region Characteristics – Channel 2

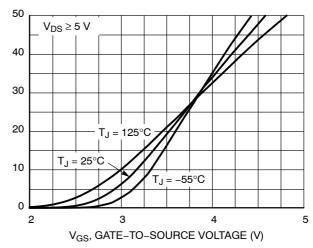


Figure 2. Transfer Characteristics - Channel 2

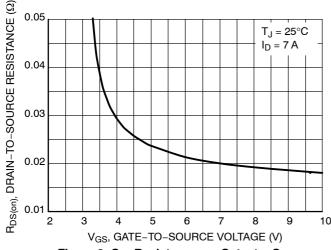


Figure 3. On-Resistance vs. Gate-to-Source Voltage - Channel 2

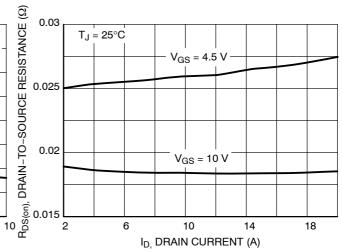


Figure 4. On-Resistance vs. Drain Current and Gate Voltage – Channel 2

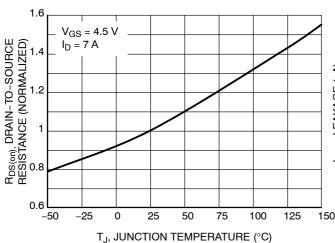
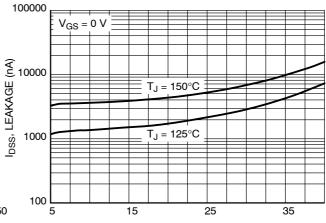


Figure 5. On–Resistance Variation with Temperature – Channel 2



V_{DS}, DRAIN-TO-SOURCE VOLTAGE (V)

Figure 6. Drain-to-Source Leakage Current vs. Voltage – Channel 2

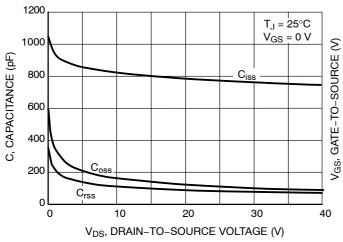


Figure 7. Capacitance Variation - Channel 2

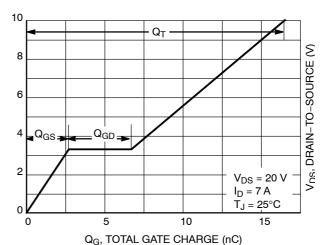


Figure 8. Gate-To-Source and
Drain-To-Source Voltage vs. Total Charge

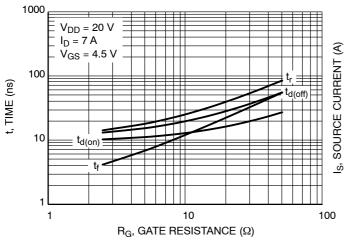


Figure 9. Resistive Switching Time Variation vs. Gate Resistance – Channel 2

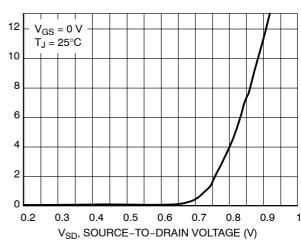


Figure 10. Diode Forward Voltage vs. Current
- Channel 2

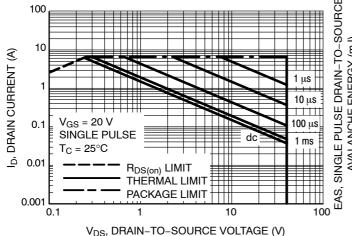
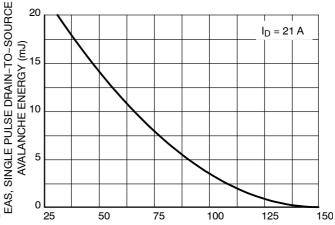


Figure 11. Maximum Rated Forward Biased Safe Operating Area – Channel 2



 $T_{J},\,STARTING\,JUNCTION\,TEMPERATURE\;(^{\circ}C)\\ \textbf{Figure 12. Maximum Avalanche Energy vs.}\\ \textbf{Starting Junction Temperature}$

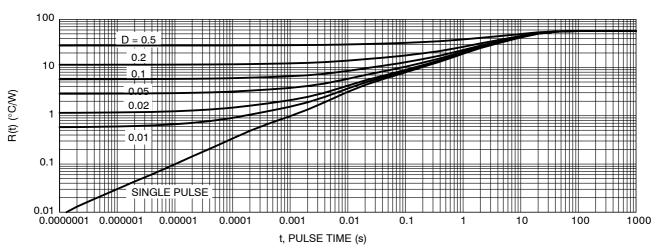
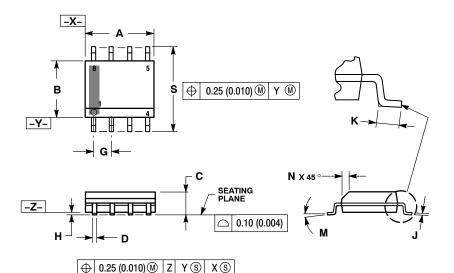


Figure 13. Thermal Response



SOIC-8 NB CASE 751-07 **ISSUE AK**

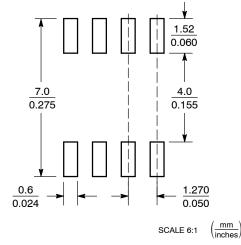
DATE 16 FEB 2011



- NOTES:
 1. DIMENSIONING AND TOLERANCING PER
- ANSI Y14.5M, 1982. CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE
- DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
- 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07.

	MILLIMETERS		INC	HES
DIM	MIN	MAX	MIN	MAX
Α	4.80	5.00	0.189	0.197
В	3.80	4.00	0.150	0.157
C	1.35	1.75	0.053	0.069
D	0.33	0.51	0.013	0.020
G	1.27 BSC		0.050 BSC	
Н	0.10	0.25	0.004	0.010
7	0.19	0.25	0.007	0.010
K	0.40	1.27	0.016	0.050
M	0 °	8 °	0 °	8 °
N	0.25	0.50	0.010	0.020
S	5.80	6.20	0.228	0.244

SOLDERING FOOTPRINT*



^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

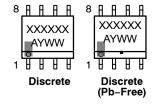
GENERIC MARKING DIAGRAM*



XXXXX = Specific Device Code = Assembly Location = Wafer Lot

= Year = Work Week

= Pb-Free Package



XXXXXX = Specific Device Code = Assembly Location Α

= Year ww

= Work Week = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb–Free indicator, "G" or microdot "■", may or may not be present. Some products may not follow the Generic Marking.

STYLES ON PAGE 2

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SOIC-8 NB CASE 751-07 ISSUE AK

DATE 16 FEB 2011

STYLE 3: PIN 1. DRAIN, PIE #1 CTOR, #1 CTOR, #2 CTOR, #1 CTOR, #2 CTOR, #1	2. ANODE 3. ANODE 4. ANODE 5. ANODE 6. ANODE 7. ANODE 8. COMMON CATHODE STYLE 8: PIN 1. COLLECTOR, DIE #1 2. BASE, #1 3. BASE, #2 4. COLLECTOR, #2 5. COLLECTOR, #2 6. EMITTER, #1 Vd STYLE 12: PIN 1. SOURCE 2. SOURCE 3. SOURCE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN 8. TYLE 16: PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #1
E PIN 1. INPUT 2. EXTERNAL BY 3. THIRD STAGE 4. GROUND E 5. DRAIN 6. GATE 3 7. SECOND STAGE 8. FIRST STAGE STYLE 11: ID PIN 1. SOURCE 1 2. GATE 1 T 3. SOURCE 2 ID 4. GATE 2 ID 5. DRAIN 2 6. DRAIN 2 7. DRAIN 1 ID 8. DRAIN 1 ID	PIN 1. COLLECTOR, DIE #1 2. BASE, #1 3. BASE, #2 4. COLLECTOR, #2 5. COLLECTOR, #2 6. EMITTER, #2 7. EMITTER, #1 Vd 8. COLLECTOR, #1 STYLE 12: PIN 1. SOURCE 2. SOURCE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN 8. TYLE 16: PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #2
ID PIN 1. SOURCE 1 2. GATE 1 T 3. SOURCE 2 ID 4. GATE 2 ID 5. DRAIN 2 6. DRAIN 2 7. DRAIN 1 ID 8. DRAIN 1 STYLE 15: RCE PIN 1. ANODE 1 E 2. ANODE 1 RCE 3. ANODE 1	PIN 1. SOURCE 2. SOURCE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN STYLE 16: PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #2
STYLE 15: RCE PIN 1. ANODE 1 E 2. ANODE 1 RCE 3. ANODE 1	PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #2
N 7. CATHODE, CON N 8. CATHODE, CON	MMON 5. COLLECTOR, DIE #2 MMON 6. COLLECTOR, DIE #2 MMON 7. COLLECTOR, DIE #1 MMON 8. COLLECTOR, DIE #1
STYLE 19: PIN 1. SOURCE 1 E 2. GATE 1 E 3. SOURCE 2 4. GATE 2 5. DRAIN 2 6. MIRROR 2 DE 7. DRAIN 1 DE 8. MIRROR 1	STYLE 20: PIN 1. SOURCE (N) 2. GATE (N) 3. SOURCE (P) 4. GATE (P) 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN
STYLE 23: E1 PIN 1. LINE 1 IN DN CATHODE/VCC 2. COMMON ANC DN CATHODE/VCC 3. COMMON ANC E3 4. LINE 2 IN DN ANODE/GND 5. LINE 2 OUT E4 6. COMMON ANC E5 7. COMMON ANC DN ANODE/GND 8. LINE 1 OUT	ODE/GND 2. EMITTER ODE/GND 3. COLLECTOR/ANODE
STYLE 27: PIN 1. ILIMIT 2. OVLO 3. UVLO 4. INPUT+ 5. SOURCE 6. SOURCE 6. SOURCE 7. SOURCE 8. DRAIN	STYLE 28: PIN 1. SW_TO_GND 2. DASIC_OFF 3. DASIC_SW_DET 4. GND 5. V MON 6. VBULK 7. VBULK 8. VIN
1 1	
;	STYLE 27: PIN 1. ILIMIT 2. OVLO 3. UVLO 4. INPUT+ E 5. SOURCE E 6. SOURCE E 7. SOURCE 8. DRAIN

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